

Date Created : **2008/01/06**  
Date Issued On : **2008/02/28**  
PCN# : **Q1080102**

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:

Name: LEE, JEONGSOO  
E-mail: JEONGSOO.LEE@fairchildsemi.com  
Phone: 82-32-680-1311

PCN Originator:

Name: LEE, JEONGSOO  
E-mail: JEONGSOO.LEE@fairchildsemi.com  
Phone: 82-32-680-1311

Implementation of change:

Expected 1st Device Shipment Date: 2008/05/25

Earliest Year/Work Week of Changed Product: WW22

Change Type Description: Data Book Specifications

Description of Change (From): Rds(on) Max limit < 480mOhm @ Vgs=10V, Id=7.5A

Description of Change (To): Rds(on) Max limit < 540mOhm @ Vgs=10V, Id=7.5A

Reason for Change : Don't meet a existing spec - Spec limit change due to not enough margin.

Qual/REL Plan Numbers : Q20080076

Qualification :

This change don't need Reliability Test.

**Results/Discussion**

Test: (High Temperature Reverse Bias)				
Lot	Device	500-HOURS	1000-HOURS	Failure Code
Q20080076AAHTRB	FQA13N50CF	0/77		
Q20080076AAHTRB	FQA13N50CF		0/77	

Product Id Description : There is a QFET product.

Affected FSIDs :

FQA13N50CF	FQA13N50CF_F109	
------------	-----------------	--